



# Growth and structural characterizations of InAs/GaAs axial nanowires heterostructures

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## LABORATORIES : NEEL, INAC

Nanowires can host combinations of materials with very different lattice parameters: the mismatch strain is efficiently relaxed on the sidewalls, enabling the formation of dislocation-free interfaces out of reach with two dimensional thin films. It is important to understand how the strain distributes as it strongly influences the band structure, and consequently the electronic and optical properties of the final device. We grow GaAs-InAs nanowires by molecular beam epitaxy using the vapour-liquid-solid mechanism with gold catalysts. Nanowires diameter, length and density are readily controllable by adjusting the

growth parameters and the catalyst diameter. We evaluate the strain and composition distribution by high-resolution scanning transmission electron microscopy (HRSTEM) together with Energy Dispersive X-ray spectroscopy. One of our important results is the observation of a 20 nm long strained region around the interface, where crystal planes bend close the sidewalls (Fig.1). Despite a 6% lattice mismatch, our structures show no dislocation when the diameter is less than 40 nm.

We are now working on the reverse structure, GaAs on InAs, in order to realize quantum dots integrated in nanowires, positioned on demand, for new photonic emitters.

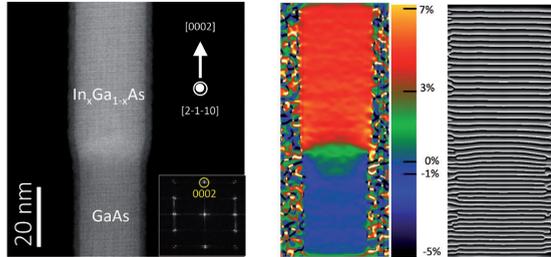


Fig. 1 : HRSTEM image of an InAs/GaAs axial heterostructure. Relative change in lattice parameter along the growth axis with respect to unstrained GaAs. HRSTEM image after Fourier filtering of the [0002] Bragg reflection.

## OUTCOMES

**Publications:** Dislocation-free axial InAs-on-GaAs nanowires on silicon, *Nanotechnology* 28, 365602 (2017).

**Oral presentations:** Journées Nationales du GDR PULSE Paris, 2017 (invited) ; Journée Nationales Nanofils, Grenoble, 2017 ; MRS Fall Meeting, Boston, USA, 2016

**Collaborations:** Pierre Verlot, University of Nottingham, UK; Marcel Verheijen, Philips Research, Eindhoven, NL.

**Leverage:** AGIR pôle PEM 2015-2016